

EPM7128 EPLD

High-Performance 128-Macrocell Device

December 1992, ver. 1

Data Sheet

Features

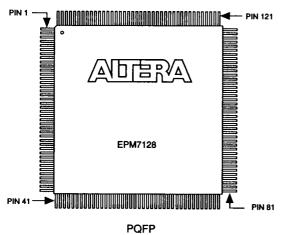
- High-density CMOS EPLD based on second-generation Multiple Array MatriX (MAX) architecture
 - 2,500 usable gates
 - Combinatorial speeds with t_{PD} = 10 ns
 - Clock frequencies up to 100 MHz

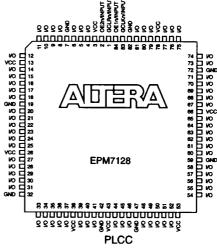
Preliminary Information

- ☐ Advanced 0.8-micron CMOS EEPROM technology
- ☐ Programmable I/O architecture with up to 100 inputs or 96 outputs
- ☐ 128 advanced macrocells to efficiently implement registered and complex combinatorial logic
- Configurable expander product-term distribution allowing up to 32 product terms in a single macrocell
- Programmable registers configurable as D, T, JK, or SR flipflops with individual Clock Enable and asynchronous Clear and Preset controls
- ☐ Independent clocking of registers from array or global Clock signals
- ☐ Programmable power-saver mode for 50% or more power reduction in each macrocell
- Available in 84-pin PLCC and 160-pin QFP packages (see Figure 1)
- ☐ Software design support featuring Altera's MAX+PLUS II development system available for PC, Sun SPARCstation, and HP 9000 Series 700 platforms

Figure 1. EPM7128 84-Pin PLCC and 160-Pin PQFP Pin-Out Diagrams

See Table 1 in this data sheet for PLCC pin-outs and Table 2 for PQFP pin-outs. Package outlines not drawn to scale.





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General Description

The Altera EPM7128 is a high-density, high-performance CMOS device based on Altera's second-generation MAX 7000 architecture. Fabricated on a 0.8-micron EEPROM technology, the EPM7128 provides 2,500 usable gates, in-system speeds of 100 MHz, and propagation delays of 10 ns. The EPM7128 architecture supports 100% TTL emulation and allows high integration of SSI, MSI, and LSI logic functions. With 128 macrocells, the EPM7128 implements complete system-level designs. It easily integrates multiple programmable logic devices such as PALs, GALs, and 22V10s. With its high performance and density, the EPM7128 provides FPGA density with PAL performance. The high density and high I/O pin count make the EPM7128 appropriate for prototyping gate arrays. Available in an 84-pin plastic J-lead chip carrier (PLCC) and a 160-pin plastic quad flat pack (PQFP), the EPM7128 accommodates both logic- and I/O-intensive designs.

The EPM7128 uses CMOS EEPROM cells to configure logic functions within the device. EPM7128 architecture is user-configurable to accommodate a variety of independent logic functions, and the device can be reprogrammed for multiple design cycles. Each device is guaranteed for 100 program and erase cycles.

The EPM7128 consists of 128 macrocells organized into 8 Logic Array Blocks (LABs). Each macrocell has a programmable-AND/fixed-OR array and a configurable register that provides D, T, JK, or SR operation with independent programmable Clock, Clock Enable, Clear, and Preset functions. For building complex logic functions, each macrocell can be supplemented with both shared expanders and high-speed parallel logic expanders to allow up to 32 product terms per macrocell.

The EPM7128 provides programmable speed/power optimization. Speed-critical portions of the design can run at high speed/full power, while the remainder runs at reduced speed/low power. This feature allows you to specify one or more macrocells to operate at 50% or less power while adding only a nominal timing delay.

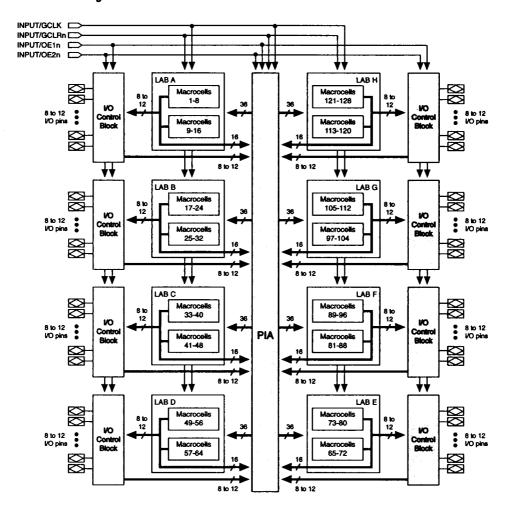
The EPM7128 is supported by the MAX+PLUS II development system, which provides a completely integrated design entry, compilation, verification, and programming environment. MAX+PLUS II software is available for 386- and 486-based PC, Sun SPARCstation, and HP 9000 Series 700 platforms. The PC-based version of MAX+PLUS II supports hierarchical graphic, text, and waveform design entry with over 300 macrofunctions. MAX+PLUS II includes the Altera Hardware Description Language (AHDL), which supports state machine, Boolean equation, and truth table entry methods. In addition, MAX+PLUS II provides highly automated compilation, automatic multi-device partitioning, timing simulation and analysis, automatic error location, device programming and verification, and a comprehensive on-line help system. MAX+PLUS II

imports and exports industry-standard EDIF 200 or Verilog netlist files, for a convenient interface to PC- and workstation-based CAE tools.

Functional Description

The EPM7128 is a 128-macrocell EPLD that has been optimized for VLSI designs. See Figure 2. It has up to 96 I/O pins that can be individually configured for input, output, or bidirectional operation. It also has four dedicated input pins that can be programmed as general-purpose inputs or high-speed, global control signals (Clock, Clear, and two Output Enable signals) for each macrocell and I/O pin.

Figure 2. EPM7128 Block Diagram



The EPM7128 contains the following architectural building blocks:

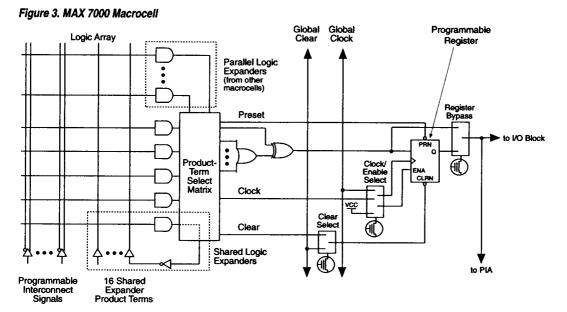
- Logic Array Blocks
- □ Macrocells
- ☐ Logic expanders (shared and parallel)
- ☐ Programmable Interconnect Array
- I/O control blocks

Logic Array Blocks

MAX 7000 architecture is based on the concept of linking small, high-performance, flexible logic array modules called Logic Array Blocks (LABs). Multiple LABs are linked together via a global bus called the Programmable Interconnect Array (PIA), which is fed by all EPM7128 dedicated inputs, I/O pins, and macrocells. The PIA routes only the signals required to implement logic in each LAB. The EPM7128 has 8 LABs, each of which contains 16 macrocells.

Macrocells

The MAX 7000 macrocell, shown in Figure 3, provides both sequential and combinatorial logic capabilities. It can be individually configured for registered or combinatorial operation. The macrocell consists of three functional blocks: the logic array, the product-term select matrix, and the programmable register.



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Combinatorial logic is implemented in the logic array, which contains five product terms. These product terms are allocated by the product-term select matrix for use as either primary logic inputs (to the OR and XOR gates) to implement combinatorial functions, or as secondary inputs for the macrocell's register Clear, Preset, Clock, and Clock Enable control functions. One product term per macrocell can be used as a shared logic expander if it is fed back into the logic array. Based on the logic requirements of the design, the product-term select matrix automatically optimizes product-term allocation.

In registered functions, each macrocell flipflop can be individually programmed for D, T, JK, or SR operation with programmable Clock control. If necessary, the flipflop can be bypassed for combinatorial operation. During design entry, the user can specify the desired flipflop type or allow MAX+PLUS II to select the most efficient flipflop operation for each registered logic function to minimize the resources needed by the design.

The programmable register can be configured in three clocking modes:

- It can be clocked from the dedicated global Clock pin (GCLK). In this mode, the flipflop is positive-edge-triggered, and the fastest Clock-tooutput performance is achieved.
- It can be clocked with the array Clock using a product term. In this mode, the flipflop can be configured for positive- or negative-edgetriggered operation. Array Clocks allow any signal source or gated logic function to clock the flipflop.
- It can be clocked from the global Clock pin and enabled by a product term. The register is enabled when the flipflop ENA input is high. Each flipflop can be activated individually while taking advantage of the fast Clock-to-output delay of the global Clock pin.

Each register also supports the asynchronous Preset and Clear functions. As shown in Figure 3, the product-term select matrix allocates product terms to control these operations. Although the register is designed for active-low Preset and Clear, active-high control is also provided when the signal is inverted within the logic array. In addition, each register Clear function can be individually connected to the EPM7128 dedicated global Clear pin (GCLRn). In this mode, the Clear function is active low.

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Logic Expanders

Although most logic functions can be implemented with the five product terms available in each macrocell, some logic functions are more complex and require additional product terms. Instead of using another macrocell to supply the needed logic resources, the MAX 7000 architecture has both shared and parallel logic expanders that provide additional product terms directly to any macrocell.

Shared Logic Expanders

Each LAB has up to 16 shared expanders, which can be viewed as a pool of uncommitted single product terms (one from each macrocell) with inverting outputs that feed back into the logic array. Each shared logic expander can be used and shared by any or all macrocells in the LAB to build complex logic functions. Shared logic expanders can also be cross-coupled to build additional buried flipflops, latches, or input registers. A small delay (t_{SEXP}) is incurred when shared logic expanders are used.

Parallel Logic Expanders

Parallel logic expanders are unused product terms from macrocells in the LAB that can be allocated to any macrocell by the product-term select matrix to implement fast, complex logic functions. With parallel logic expanders, up to 20 product terms can directly feed the macrocell OR logic (5 product terms from the macrocell and 15 parallel logic expanders provided by other macrocells in the LAB).

The MAX+PLUS II Compiler can automatically route parallel logic expanders to the necessary macrocells in sets of 1 to 5. Each set of expanders incurs a small, incremental timing delay (t_{PEXP}). For example, if a macrocell requires 14 product terms, the Compiler will allocate 2 sets of parallel logic expanders (the first set equals 5 product terms, the second set equals 4 product terms, increasing the total delay by $2 \times t_{PEXP}$), in addition to the 5 product terms already in the macrocell.

The EPM7128 EPLD can use shared and parallel logic expanders to allocate additional product terms to any macrocell, ensuring that logic is synthesized with the fewest logic resources to obtain the fastest possible speed.

Programmable Interconnect Array

Logic is routed between the EPM7128 LABs on the Programmable Interconnect Array (PIA). This global bus is a programmable path that allows any signal source to reach any destination on the device. Although EPM7128 dedicated inputs, I/O pin feedbacks, and macrocell feedbacks all feed the PIA, the PIA routes only the required signals needed by each macrocell back into each LAB.

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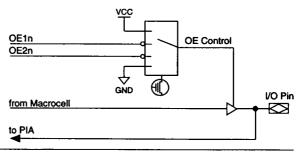
While the routing delays of channel-based routing schemes in masked or field-programmable gate arrays are cumulative, variable, and path-dependent, the MAX 7000 PIA has a fixed delay. The PIA eliminates skew between signals, making timing performance easy to predict.

VO Control Blocks

The I/O control block, shown in Figure 4, allows each I/O pin to be individually configured for input, output, or bidirectional operation. All I/O pins have a tri-state buffer that is connected to one of two global active-low Output Enable pins (OE1n and OE2n) or directly to GND or VCC. When the I/O tri-state buffer is connected to GND, the output is tri-stated (high impedance) and the I/O pin can be used as a dedicated input. When the I/O tri-state buffer is connected to VCC, the output is enabled.

The EPM7128 provides dual feedback. The macrocell and pin feedbacks are independent. When an I/O pin is configured as an input, the associated macrocell can be used for buried logic.

Figure 4. MAX 7000 I/O Control Block



Programmable Speed/Power Control

The EPM7128 offers a power-saver mode that supports low-power operation across user-defined signal paths or the entire device. This feature allows total power dissipation to be reduced by 50% or more, since only a small number of all gates operates at maximum frequency in most logic applications.

Each macrocell in the EPM7128 can be individually programmed by the designer for either high-speed or low-power operation. As a result, speed-critical paths in the design can run at high speed, while remaining paths can operate at reduced power. Macrocells that run at low power incur a nominal timing delay adder (t_{LPA}) for the t_{LAD} , t_{LAC} , t_{EN} , t_{SEXP} , and t_{ACL} parameters.

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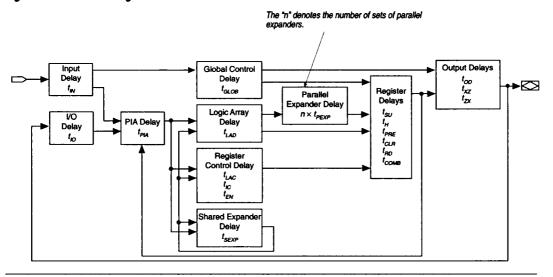
Design Security

The EPM7128 contains a programmable Security Bit that controls access to the data programmed into the device. When this bit is programmed, a proprietary design implemented in the device cannot be copied or retrieved. This feature provides a high level of design security, since programmed data within EEPROM cells is invisible. The Security Bit that controls this function, as well as all other program data, is reset when the device is erased.

Timing Model

Timing within the EPM7128 can be analyzed either with the MAX+PLUS II software or with the timing model shown in Figure 5. The EPM7128 has fixed internal delays that allow the user to determine the worst-case timing for any design. For complete timing information, MAX+PLUS II software provides complete timing simulation, point-to-point delay prediction, and detailed timing analysis for system-level performance evaluation.

Figure 5. MAX 7000 Timing Model



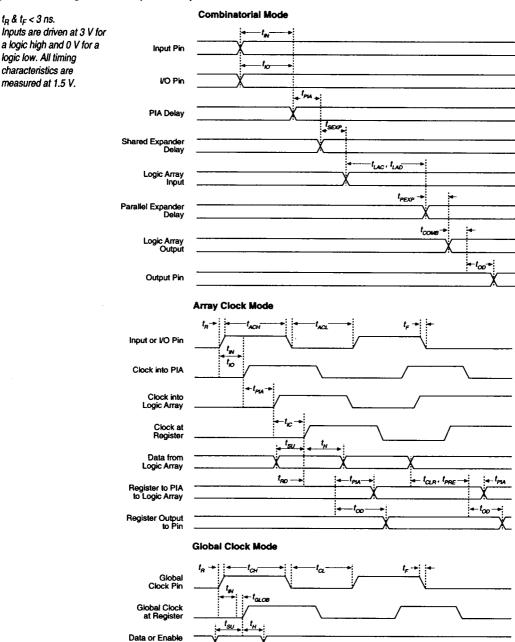
Timing information can be calculated with the timing model and the timing parameters for a particular device. External timing parameters are derived from the sum of internal parameters and represent pin-to-pin timing delays. Figure 6 shows the internal timing relationship for internal and external delay parameters. Actual worst-case timing can be calculated in a timing simulation with the MAX+PLUS II Simulator, in a timing analysis with the MAX+PLUS II Timing Analyzer, or with other supported CAE simulators.

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 t_R & t_F < 3 ns.

logic low. All timing characteristics are measured at 1.5 V.

Figure 6. Switching Waveforms (Part 1 of 2)

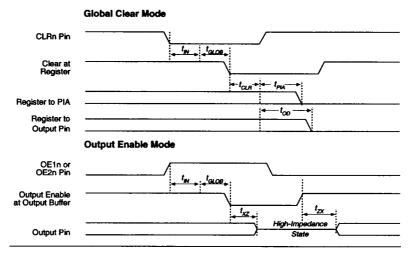


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(Logic Array Output)

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Figure 6. Switching Waveforms (Part 2 of 2)



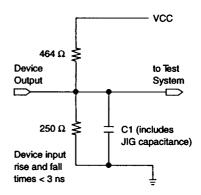
Generic Testing

The EPM7128 is functionally tested and guaranteed. Complete testing of each programmable EEPROM bit and all internal logic elements ensures 100% programming yield. AC test measurements are made under the conditions shown in Figure 7.

Test patterns can be used and then erased during early stages of the production flow. This facility to use application-independent, general-purpose tests, called generic testing, is unique among user-configurable logic devices.

Figure 7. EPM7128 AC Test Conditions

Power supply transients can affect AC measurements. Simultaneous transitions of multiple outputs should be avoided for accurate measurement. Threshold tests must not be performed under AC conditions. Large-amplitude, fast ground current transients normally occur as the device outputs discharge the load capacitances. When these transients flow through the parasitic inductance between the device ground pin and the test system ground, it can create significant reductions in observable noise immunity.



MAX+PLUS II Development System

The EPM7128 is supported by Altera's MAX+PLUS II development system. MAX+PLUS II supports Altera's Classic, MAX 5000/EPS464, MAX 7000, and FLEX 8000 device families.

Designs can be entered as logic schematics with the Graphic Editor; as state machines, truth tables, and Boolean equations with the Altera Hardware Description Language (AHDL); or as waveforms with the Waveform Editor. Logic synthesis and minimization automatically optimize the logic of a design. MAX+PLUS II also provides automatic design partitioning into multiple devices from the same family. Design verification and timing analysis are performed with the built-in Simulator and Timing Analyzer. Errors in a design are automatically located and highlighted in the original design files.

MAX+PLUS II runs on IBM PC-AT, PS/2, and compatible computers, as well as Sun SPARCstations and HP 9000 Series 700 workstations. The software gives designers the tools to quickly and efficiently create complex logic designs. MAX+PLUS II also provides an EDIF netlist interface for additional design entry and simulation support with popular CAE tools from Cadence, Logic Modeling, Mentor Graphics, Synopsis, Viewlogic and others. Further details about the MAX+PLUS II development system are available in the MAX+PLUS II Programmable Logic Development System & Software Data Sheet.

Device Programming

The EPM7128 can be programmed on an IBM PC-AT, PS/2, or compatible computer with an Altera Logic Programmer card, the Master Programming Unit (MPU), and the PLMJ7128-84 or PLMQ7128-160 device adapter. The MPU supports device open- and short-circuit testing and performs continuity checking to ensure adequate electrical contact between the programming adapter and the device.

MAX+PLUS II software uses test vectors developed with the Waveform Editor to functionally test the programmed device. For added design verification, designers can compare the functional behavior of the EPM7128 with the results of timing simulation.

In addition, Data I/O and a variety of third-party manufacturers provide programming support for Altera devices.

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Absolute Maximum Ratings See Note (1) and Operating Requirements for EPLDs in the 1992 Data Book.

Symbol	Parameter	Conditions	Min	Max	Unit
v _{cc}	Supply voltage	With respect to GND	-2.0	7.0	٧
V _I	DC input voltage	See Note (2)	-2.0	7.0	v
I _{MAX}	DC V _{CC} or GND current			800	mA
lout	DC output current, per pin		-25	25	mA
PD	Power dissipation			4000	mW
T _{STG}	Storage temperature	No bias	-65	150	۰c
T _{AMB}	Ambient temperature	Under bias	-65	135	۰c
Tj	Junction temperature	Under bias		150	۰c

Recommended Operating Conditions

Symbol	Parameter	Conditions	Min	Max	Unit
v _{cc}	Supply voltage		4.75	5.25	V
V _I	Input voltage		0	v _{cc}	٧
v _o	Output voltage		0	Vcc	٧
TA	Operating temperature	For commercial use	0	70	۰c
t _R	Input rise time			30	ns
t _F	Input fall time			30	ns

DC Operating Conditions See Notes (3), (4)

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{IH}	High-level input voltage		2.0		V _{CC} + 0.3	٧
V _{IL}	Low-level input voltage		-0.3		0.8	٧
V _{OH}	High-level TTL output voltage	I _{OH} = -4 mA DC	2.4			٧
VOL	Low-level output voltage	I _{OL} = 8 mA DC			0.45	٧
I _I	Input leakage current	V ₁ = V _{CC} or GND	-10		10	μΑ
loz	Tri-state output off-state current	V _O = V _{CC} or GND	-40		40	μΑ
I _{CC1}	V _{CC} supply current (standby, low-power mode)	V _I = GND, No load		90		mA
I _{CC2}	V _{CC} supply current (active, low-power mode)	V _I = GND, No load, f = 1.0 MHz, See Note (5)		100		mA

Capacitance See Note (6)

Symbol	Parameter	Conditions	Min	Max	Unit
CIN	Input capacitance	V _{IN} = 0 V, f = 1.0 MHz		15	pF
C _{OUT}	Output capacitance	V _{OUT} = 0 V, f = 1.0 MHz		15	pF

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AC Operating Conditions See Note (4)

Externa	l Timing Parameters		EPM71	28-1 <i>(9)</i>	EPM	7128-2	EPM:	7128-3	EPM	7128-4	
Symbol	Parameter	Conditions	Min	Max	Min	Max	Min	Max	Min	Max	Unit
t _{PD1}	Input to non-reg. output	C1 = 35 pF		10		12		15		20	ns
tPD2	I/O input to non-reg. output	See Figure 7		10	<u> </u>	12		15		20	ns
tsu	Global clock setup time		8		9		11		12	-	ns
tH	Global clock hold time		0		0		0		0		ns
t _{CO1}	Global clock to output delay	C1 = 35 pF, See Fig. 7		5		6		8		13	ns
t _{CH}	Global clock high time		4		4		5		6		ns
tCL	Global clock low time		4		4		5		6		ns
^t ASU	Array clock setup time		3		3		4		5		ns
^t AH	Array clock hold time		3		3		4		5		ns
tACO1	Array clock to output delay	C1 = 35 pF, See Fig. 7		10		12		15		20	ns
^t ACH	Array clock high time		4		5		6		8		ns
^t ACL	Array clock low time		4		5		6		8		ns
^t CNT	Minimum global clock period			10		11		13		15	ns
f CNT	Max. int. global clock freq.	See Note (5)	100		90.9		76.9		66.6		MHz
TACNT	Minimum array clock period			10		11		13		15	ns
FACNT	Max. int. array clock freq.	See Note (5)	100		90.9		76.9		66.6		MHz
f MAX	Maximum clock frequency	See Note (7)	125		125		100		83.3		MHz
Internal	Timing Parameters		EPM7	128-1	EPM7	128-2	ЕРМ7	EPM7128-3 EPM7128-4		PM7128-4	
Symbol	Parameter	Conditions	Min	Max	Min	Max	Min	Max	Min	Max	Unit
t _{IN}	Input pad & buffer delay			1		1		2		5	ns
110	I/O input pad & buffer delay			1		1		2		5	ns
SEXP	Shared expander delay			5		7		9		10	ns
t PEXP	Parallel expander delay			0.8		1		1		3	ns
tLAD	Logic array delay			5		6		6		6	ns
LAC	Logic control array delay		-	5		6		6		6	ns
OD (Output buffer & pad delay	C1 = 35 pF		2		3		4		5	ns
tzx (Output buffer enable delay	See Figure 7		5		6		6		9	ns
txz (Output buffer disable delay	C1 = 5 pF		5		6		6		9	ns
tsu I	Danista de la di								5		ns
, 10	Register setup time		3		3		4	- 1	ગ		
H	Register hold time		3		3		4		5		ns
				1		1		1		1	
RD I	Register hold time			1 1		1 1		1 1		1 1	ns ns
COMB	Register hold time Register delay										ns
COMB	Register hold time Register delay Combinatorial delay			1		1		1		1	ns ns ns
COMB COMB COMB COMB COMB COMB COMB COMB	Register hold time Register delay Combinatorial delay Array clock delay			1 5		1 6		1 6		1 6	ns ns ns MHz
COMB COMB COMB COMB COMB COMB COMB COMB	Register hold time Register delay Combinatorial delay Array clock delay Register enable time			1 5 5		1 6 6		1 6 6		1 6 6	ns ns ns MHz
COMB COMB COMB COMB COMB COMB COMB COMB	Register hold time Register delay Combinatorial delay Array clock delay Register enable time Global control delay			1 5 5 1		1 6 6 1		1 6 6 1		1 6 6 2 4	ns ns ns MHz
PRD FOR PRE FO	Register hold time Register delay Combinatorial delay Array clock delay Register enable time Global control delay Register preset time			1 5 5 1 3		1 6 6 1 3		1 6 6 1 4		1 6 6 2	ns ns ns MHz

Notes to tables:

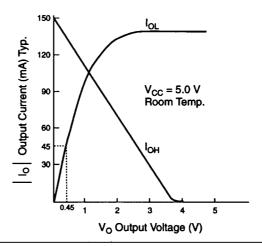
- Operating devices outside the Absolute Maximum Ratings may permanently damage the devices. Extended operation at the Absolute Maximum Ratings may adversely affect device reliability.
- (2) Minimum DC input is -0.3 V. During transitions, the inputs may undershoot to -2.0 V or overshoot to 7.0 V for periods shorter than 20 ns under no-load conditions.
- (3) Typical values are for $T_A = 25^{\circ} C$ and $V_{CC} = 5 V$.
- (4) Operating conditions: $V_{CC} = 5 V \pm 5\%$, $T_A = 0^{\circ} C$ to $70^{\circ} C$ for commercial use.
- (5) Measured with a device programmed as a 16-bit loadable, enabled up/down counter in each LAB.
- (6) Capacitance measured at 25° C. Sample tested only. OE1n (high-voltage pin during programming) has a capacitance of 25 pF.
- (7) The f_{MAX} values represent the highest frequency for pipelined data.
- (8) The t_{LPA} parameter must be added to the t_{LAD} , t_{LAC} , t_{EN} , t_{SEXP} , and t_{ACL} parameters for macrocells running in low-power mode.
- This version is under development. Contact Altera Marketing at (408) 894-7000 for information on availability.

Product Availability

	Grade	Availability
Commercial	(0° C to 70° C)	EPM7128-2, EPM7128-3, EPM7128-4
Industrial	(-40° C to 85° C)	Consult factory
Military	(-55° C to 125° C)	Consult factory

Figure 8 shows output drive characteristics of EPM7128 I/O pins.

Figure 8. EPM7128 Output Drive Characteristics



Tables 1 and 2 show the pin-outs for the EPM7128 84-pin PLCC and 160-pin PQFP packages, respectively.

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Table 1. EPM7128 84-Pin PLCC Pin-Outs Note (1)											
LAB	MC	Pin	LAB	MC	Pin	LAB	MC	Pin	LAB	MC	Pin
Α	1	_	В	17	22	С	33	_	D	49	41
Α	2	-	В	18	-	С	34	_	D	50	_
Α	3	12	В	19	21	С	35	31	D	51	40
Α	4	-	В	20	-	С	36	-	D	52	_
Α	5	11	В	21	20	C	37	30	D	53	39
Α	6	10	В	22	_	С	38	29	D	54	-
Α	7	-	В	23	-	C	39	-	D	55	-
Α	8	9	В	24	18	С	40	28	D	56	37
Α	9	-	В	25	17	С	41	-	D	57	36
Α	10	-	В	26	-	C	42	-	D	58	_
Α	11	8	В	27	16	С	43	27	D	59	35
Α	12	-	В	28	-	С	44	-	D	60	-
Α	13	6	В	29	15	С	45	25	D	61	34
Α	14	5	В	30	-	С	46	24	D	62	-
Α	15	-	В	31	-	С	47	-	D	63	-
Α	16	4	В	32	14	С	48	23	D	64	33
Ε	65	44	F	81	-	G	97	63	Н	113	_
Ε	66	-	F	82	-	G	98	-	Н	114	-
Ε	67	45	F	83	54	G	99	64	Н	115	73
Ε	68	-	F	84	-	G	100	-	Н	116	_
Ε	69	46	F	85	55	G	101	65	н	117	74
Ε	70	-	F	86	56	G	102	-	Н	118	75
Ε	71	-	F	87	-	G	103	-	Н	119	-
Ε	72	48	F	88	57	G	104	67	Н	120	76
E	73	49	F	89	-	G	105	68	Н	121	-
Ε	74	-	F	90	- 1	G	106	-	Н	122	-
Ε	75	50	F	91	58	G	107	69	н	123	77
E	76	-	F	92	-	G	108		Н	124	-
Ε	77	51	F	93	60	G	109	70	Н	125	79
Ε	78	-	F	94	61	G	110	- 1	н	126	80
E	79	-	F	95	-	G	111	-	Н	127	-
E	80	52	F	96	62	G	112	71	Н	128	81

EPM7128 84-pin PLCC inputs, VCC, and GND pin-outs:

VCC: 3, 13, 26, 38, 43, 53, 66, 78 GND: 7, 19, 32, 42, 47, 59, 72, 82

GCLK: 83; OE1n: 84; OE2n: 2; GCLRn: 1

(1) A dash indicates a buried macrocell.

EPM7128 160-pin PQFP dedicated inputs, VCC, GND and No Connect (NC) pin-outs:

VCC: 8, 26, 55, 61, 79, 104, 133, 143 **GND**: 17, 42, 60, 66, 95, 113, 138, 148

GCLK: 139; OE1n: 140; OE2n: 142; GCLRn: 141

NC: 1, 2, 3, 4, 5, 6, 7, 34, 35, 36, 37, 38, 39, 40, 44, 45, 46, 47, 74, 75, 76, 77, 81, 82, 83, 84, 85, 86, 87, 114, 115, 116, 117, 118, 119, 120, 124, 125,

126, 127, 154, 155, 156, 157

Note:

(1) A dash indicates a buried macrocell.

Package Outlines

Figure 9 shows the package outline for the 84-pin plastic PLCC package. Figure 10 shows the package outline for the 160-pin plastic QFP package. Consult Altera for alternative package availability.

Figure 9. EPM7128 84-Pin Plastic J-Lead Chip Carrier (PLCC)

Dimensions are shown in inches/(millimeters).

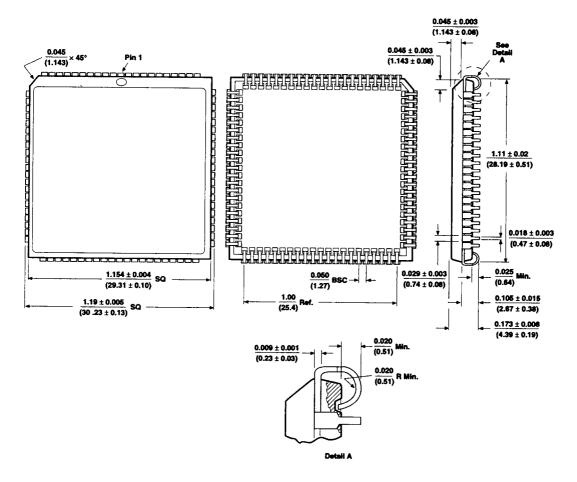
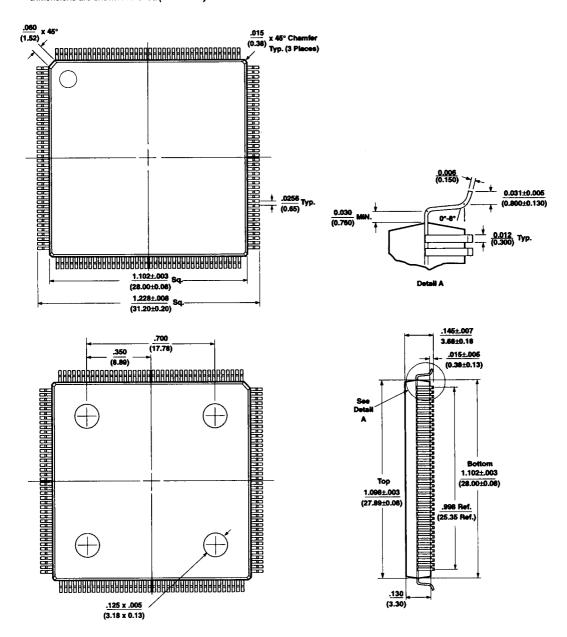


Figure 10. EPM7128 160-pin Plastic Quad Flat Pack (PQFP)

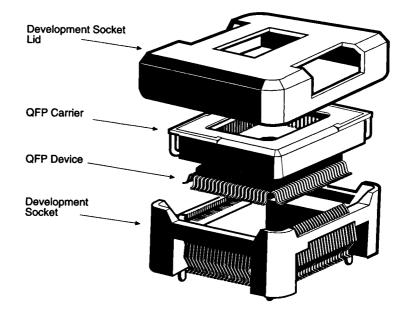
Dimensions are shown in inches/(millimeters).



QFP Carrier & Development Socket

The EPM7128 devices in QFP packages are shipped in special plastic carriers to protect the leads. The carrier is used with a prototype development socket and special programming hardware available from Altera. With this carrier technology, the device can be programmed, tested, erased, and reprogrammed without exposing the leads to mechanical stress (see Figure 11). Refer to the QFP Carrier & Development Socket Data Sheet for more information and carrier dimensions.

Figure 11. QFP Carrier and Development Socket





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U.S. and European patents pending

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